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1 Construction of multi-resolution terrain models using hierarchical Delaunay triangulated irregular networks*Shu-Jeng Huang; Din-Chang Tseng;*

Geoscience and Remote Sensing, 1997. IGARSS '97. 'Remote Sensing - A Science Vision for Sustainable Development', 1997 IEEE International , Volume: 4 , 3 Aug. 1997

Pages:1999 - 2001 vol.4

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Computer , Volume: 25 , Issue: 7 , July 1992

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Emerging Technologies and Factory Automation, 1994. ETFA '94., IEEE Symposium , 6-10 Nov. 1994

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System Sciences, 1988. Vol.II. Software Track, Proceedings of the Twenty-Fifth Annual Hawaii International Conference on , Volume: 2 , 5-8 Jan. 1988

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- Conference Proceedings
- Standards

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- Basic
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